



DCR5450W22

Phase Control Thyristor

DS5752-2.3 September 2007 (LN25537)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR5450W22 DCR5450W20 DCR5450W18	2200 2000 1800	$\begin{split} T_{vj} &= \text{-}40^{\circ}\text{C to 125}^{\circ}\text{C}, \\ I_{DRM} &= I_{RRM} = 200\text{mA}, \\ V_{DRM}, V_{RRM} t_p &= 10\text{ms}, \\ V_{DSM} \& V_{RSM} &= \\ V_{DRM} \& V_{RRM} + 100V \\ respectively \end{split}$

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR5450W22

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

 $\begin{array}{lll} V_{DRM} & 2200V \\ I_{T(AV)} & 5240A \\ I_{TSM} & 72500A \\ dV/dt^* & 2000V/\mu s \\ dI/dt & 500A/\mu s \end{array}$

* Higher dV/dt selections available

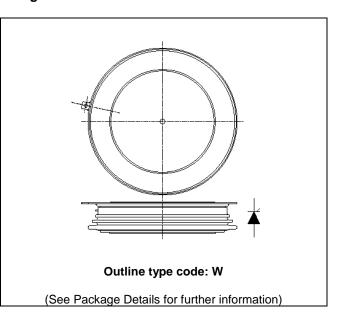


Fig. 1 Package outline





CURRENT RATINGS

$T_{case} = 60$ °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Si	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	5240	А
I _{T(RMS)}	RMS value	-	8230	А
I _T	Continuous (direct) on-state current	-	7340	А

SURGE RATINGS

Symbol Parameter		Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, T _{case} = 125°C	72.5	kA
l ² t	I ² t for fusing	$V_R = 0$	26.3	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled DC		-	0.00631	°C/W
		Single side cooled	Anode DC	-	0.01115	°C/W
			Cathode DC	-	0.01453	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 76kN Double side		-	0.0014	°C/W
		(with mounting compound)	Single side	-	0.0028	°C/W
T _{vj}	Virtual junction temperature	Blocking V _{DRM} / _{VRRM}		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
F _m	Clamping force			68.0	84.0	kN





DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125°C		-	200	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V_{DRM} , $T_j = 125$ °C, ga	ate open	-	2000	V/µs
dl/dt	Rate of rise of on-state current	From 67% V _{DRM} to 2x I _{T(AV)}	Repetitive 50Hz	-	250	A/µs
		Gate source 30V, 10Ω,	Non-repetitive	-	500	A/µs
		$t_r < 0.5 \mu s, T_j = 125^{\circ}C$				
V _{T(TO)}	Threshold voltage – Low level	500A to 3000A at T _{case} = 125	5°C	-	0.72	V
	Threshold voltage – High level	3000A to 10000A at T _{case} = 125°C		-	0.84	V
r _T	On-state slope resistance – Low level	500A to 3000A at T _{case} = 125°C		-	0.1134	mΩ
	On-state slope resistance – High level	3000A to 10000A at T _{case} = 125°C		-	0.0734	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10Ω		0.5	1.5	μs
		$t_r = 0.5 \mu s, T_j = 25^{\circ}C$				
tq	Turn-off time	$T_j = 125$ °C, $V_R = 200$ V, $dI/dt = 1$ A/ μ s,		50	150	μs
		dV _{DR} /dt = 20V/μs linear				
Qs	Stored charge	$I_T = 2000A$, $T_j = 125$ °C, $dI/dt - 1A/\mu s$,		460	1600	μC
ال	Latching current	$T_j = 25^{\circ}C, V_D = 5V$		-	3	А
I _H	Holding current	$T_j = 25$ °C, $R_{G-K} = \infty$, $I_{TM} = 500A$, $I_T = 5A$		-	300	mA





GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V_{GT}	Gate trigger voltage	$V_{DRM} = 5V$, $T_{case} = 25$ °C	1.5	V
V_{GD}	Gate non-trigger voltage	At V _{DRM} , T _{case} = 125°C	TBD	V
I _{GT}	Gate trigger current	$V_{DRM} = 5V$, $T_{case} = 25$ °C	250	mA
I _{GD}	Gate non-trigger current	V _{DRM} = 5V, T _{case} = 25°C	TBD	mA

CURVES

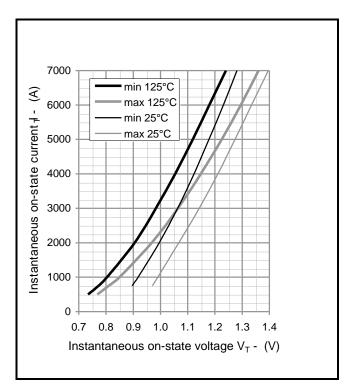


Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$

Where A = 0.7793769

B = -0.04481

 $C = -3.68 \times 10^{-6}$

D = 0.0119692

these values are valid for $T_j = 125^{\circ}C$ for $I_T 500A$ to 10000A

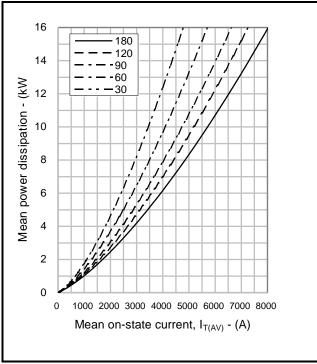


Fig.3 On-state power dissipation - sine wave

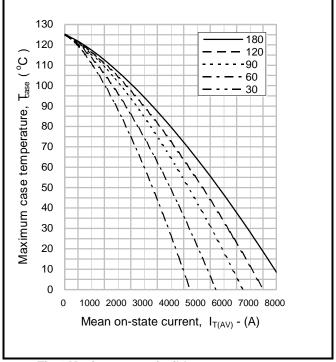


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

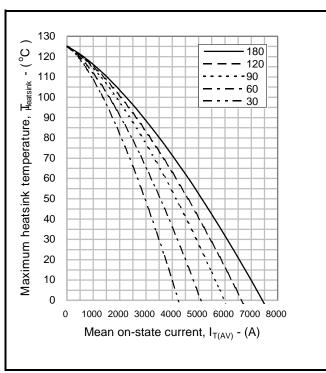


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

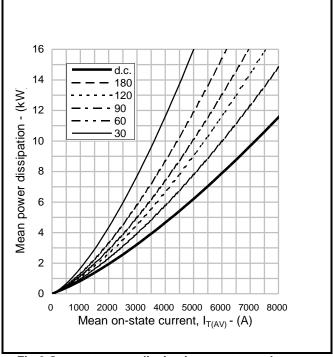


Fig.6 On-state power dissipation - rectangular wave

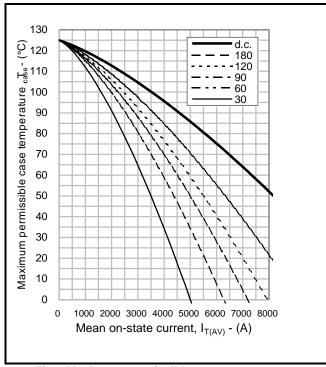


Fig.7 Maximum permissible case temperature, double side cooled – rectangular wave

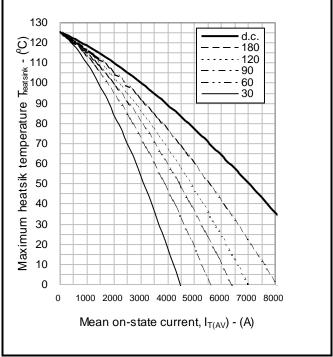
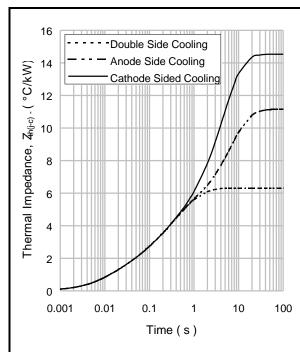


Fig.8 Maximum permissible heatsink temperature, double side cooled – rectangular wave



		1	2	3	4
Double side cooled	R _i (°C/kW)	0.8816	1.2993	2.8048	1.3305
	T _i (s)	0.0106818	0.058404	0.3584979	1.1285
Anode side cooled	R _i (°C/kW)	1.5197	3.2398	5.7622	0.6312
	T _i (s)	0.0170581	0.2424644	6.013	15.364
Cathode side cooled	R _i (°C/kW)	1.4106	2.4667	6.7451	3.9054
	T _i (s)	0.0158344	0.1786951	3.6201	6.196

 $Z_{th} = \sum_{i} [R_i x (1-exp. (t/t_i))]$ [1

 $\Delta R_{\text{th(j-c)}}$ Conduction

Tables show the increments of thermal resistance $R_{\text{th(j-c)}}$ when the device operates at conduction angles other than d.c.

Double side cooling				Anode Side Cooling				
	$\Delta Z_{th}(z)$		$\Delta Z_{th}(z)$				ΔZ_t	_h (z)
θ°	sine.	rect.		θ°	sine.	rect.		
180	1.00	0.67		180	0.94	0.64		
120	1.16	0.97		120	1.08	0.91		
90	1.33	1.13		90	1.23	1.06		
60	1.48	1.31		60	1.37	1.22		
30	1.61	1.51		30	1.47	1.38		
15	1.66	1.61		15	1.52	1.47		

Ca	thode Sided	thode Sided Cooling				
	$\Delta Z_{th}(z)$					
θ°	sine.	rect.				
180	0.95	0.65				
120	1.09	0.92				
90	1.25	1.07				
60	1.38	1.23				
30	1.49	1.40				
4.5		4 40				

Fig.9 Maximum (limit) transient thermal impedance - junction to case (°C/kW)

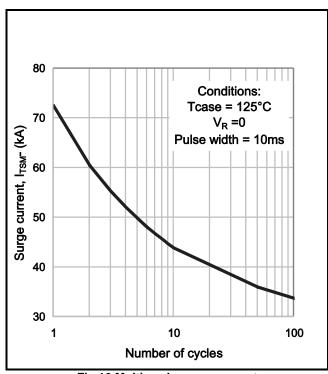


Fig.10 Multi-cycle surge current

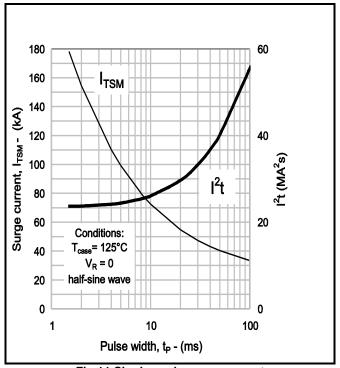


Fig.11 Single-cycle surge current

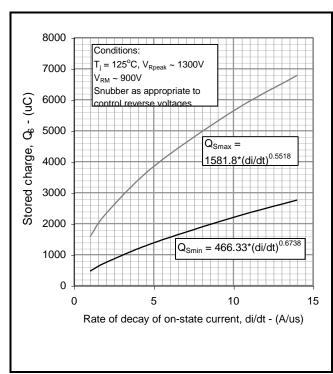


Fig.12 Stored charge

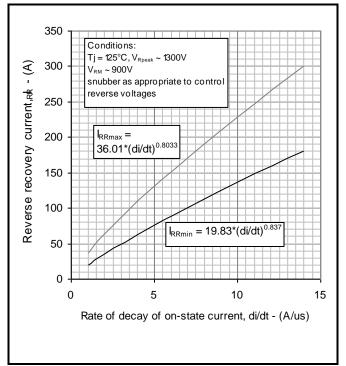


Fig.13 Reverse recovery current

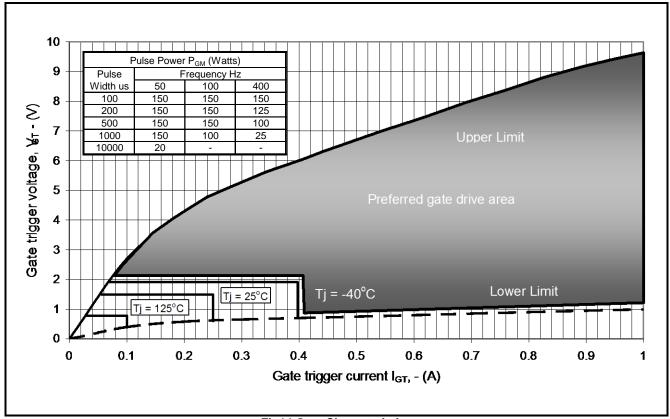


Fig14 Gate Characteristics

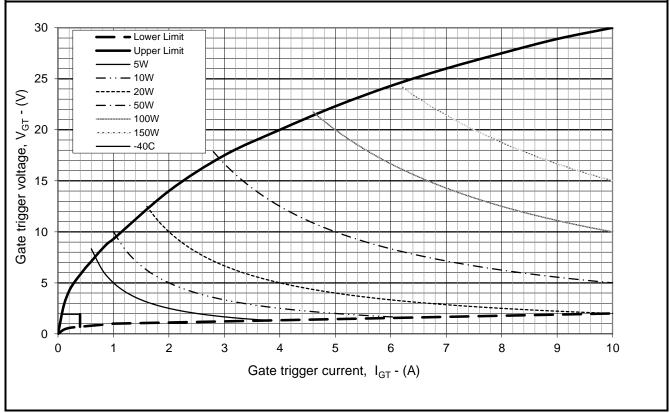


Fig. 15 Gate characteristics





PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

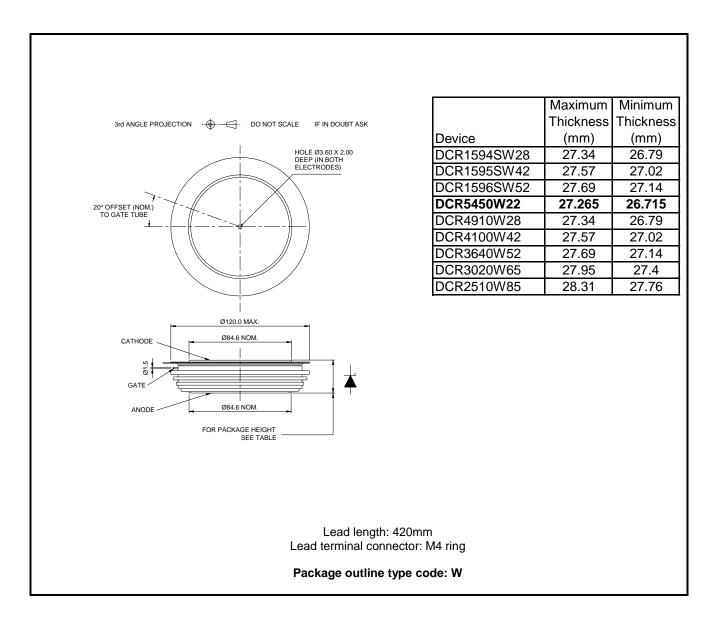


Fig.16 Package outline





POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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